



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Daniel Krahmer et al.      Art Unit : Unknown  
Serial No. : 10/817,527      Examiner : Unknown  
Filed : April 1, 2004  
Title : OBJECTIVE WITH FLUORIDE CRYSTAL LENSES

MAIL STOP AMENDMENT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Copies of the references listed on the attached form PTO-1449 are enclosed, except for US publications and patents which should be readily available to the Examiner. A Search Report issued in the priority PCT application (PCT/EP02/05050) showing the degree of relevance for the non-English documents is enclosed. Applicants also bring to the Examiner's attention commonly owned and co-pending U.S.S.N. 10/931,745.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

CERTIFICATE OF MAILING BY FIRST CLASS MAIL

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November 8, 2004

Jessica Brown

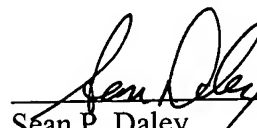
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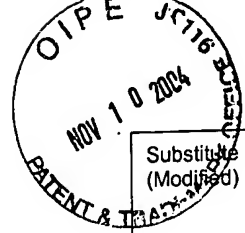
Attorney's Docket No.: 17979-006002 / 02045PUS  
CON

Respectfully submitted,

Date: 4/8/04

  
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Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
17979-006002Application No.  
10/817,527**Information Disclosure Statement  
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant  
Daniel Krahmer et al.Filing Date  
April 1, 2004

Group Art Unit

**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	5,652,745	7/29/1997	Noguchi et al.			
	AB	1,332,410	3/2/1920	Potts Oscero W.			
	AC	20040136084	07/15/2004	Unno et al.			
	AD	20040050318	03/18/2004	Sakai, Keita			
	AE	20040008348	01/15/2004	Kishikawa et al.			
	AF	20040156051	08/12/2004	Takeuchi et al.			
	AG	6,765,717	07/20/2004	Allan et al.			
	AH	20030168597	09/11/2003	Webb et al.			
	AI	6,782,075	8/24/2004	Pell			
	AJ	6,775,063	8/10/2004	Shiraishi			
	AK	6,788,389	9/7/2004	Fujishima, et al.			
	AL	20040089023	5/13/2004	Hiraiwa et al.			
	AM	20030197946	10/23/2003	Omura			
	AN	6,782,074	8/24/2004	Sakuma			

**Foreign Patent Documents or Published Foreign Patent Applications**

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AO	EP0103485	3/21/1984	Europe				
	AP	EP0857985	8/12/1998	Europe				
	AQ	EP1063551	12/27/0000	Europe				
	AR	DE19807120	8/26/1999	Germany				
	AS	JP09166710	6/24/1997	Japan			x	
	AT	JP2001108801	4/20/2001	Japan			abstrt	
	AU	JP2000331927	11/30/2000	Japan			abstrt	
	AV	WO91/14189	9/19/1991	WIPO				
	AW	WO00/70407	11/23/2000	WIPO				
	AX	WO02/093201	11/21/2002	WIPO				

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 17979-006002	Application No. 10/817,527
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Daniel Krahmer et al.	
		Filing Date April 1, 2004	Group Art Unit

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AY	WO03/003072	1/9/2003	WIPO				
	AZ	WO03/003429	1/9/2003	WIPO				
	AAA	WO03/007045	1/23/2003	WIPO				

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	ABB	Burnett, J. H. et al., "Intrinsic Birefringence in calcium fluoride" Preprint handed out at 2 <sup>nd</sup> International Symposium on 157nm Lithography in Dana Point, California, May 15, 2001
	ACC	Mulkens, J. et al. "157-nm technology: Where are we today?" Optical Microlithography XV. 2002. Vol. 4691, 613-625. Proceedings of the SPIE-Int. Soc. Opt. Eng., Santa Clara, CA, US, March 5-8 2002
	ADD	Nogawa H., et al. "System design of a 157 nm scanner". Optical Microlithography XV. 2002. Vol. 4691, 602-612 Proceedings of the SPIE-Int. Soc. Opt. Eng., Santa Clara, CA, US, March 5-8 2002.
	AEE	Shiraishi, N. et al. "Progress of Nikon's F2 Exposure Tool Development". Proceedings of the SPIE, SPIE, Bellingham, VA, US March 5, 2002 Vol. 4691. March 5, 2002. 594-601.
	AFF	Burnett et al., "Preliminary Determination of an Intrinsic Birefringence in CaF <sub>2</sub> ", dated May 7, 2001, 2 <sup>nd</sup> International Symposium on 157nm Lithography in Dana Point, California, May 15, 2001

Examiner Signature	Date Considered
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